

Search Notes

Application/Control N .

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Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent und r
R examination

AKIYAMA ET AL.

Art Unit

1745

SEARCHED

Class	Subclass	Date	Examiner
429	12	7/19/2006	DWY
429	34	7/19/2006	DWY
429	35	7/19/2006	DWY

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	7/19/2006	DWY